

## Diode

Emitter Controlled 4 Medium Power Technology IDC73D120T8M

Data Sheet

### Industrial Power Control

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# IDC73D120T8M

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# IDC73D120T8M

### **Diode Chip in Emitter Controlled 4 Medium Power Technology**

#### Features:

- 1200V Emitter Controlled 4 technology 110µm chip
- Soft, fast switching
- Low reverse recovery charge
- Small temperature coefficient

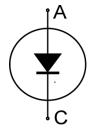
#### **Recommended for:**

Low / medium power modules

#### Applications:

•

• Low / medium power drives



| Chip Type    | V <sub>R</sub> | <b>I</b> <sub>Fn</sub> | Die Size        | Package      |
|--------------|----------------|------------------------|-----------------|--------------|
| IDC73D120T8M | 1200V          | 150A                   | 9.00mm x 8.15mm | Sawn on foil |

#### **Mechanical Parameters**

|                                     | 9.00 x 8.15<br>73.35                               | mm <sup>2</sup>  |  |  |
|-------------------------------------|--|--|--|--|
|                                     | 73.35  | mm <sup>2</sup>  |  |  |
|                                     |  |  |  |  |
|                                     | 8.026 x 7.196                                      |  |  |  |
|                                     | 110 µn   |  |  |  |
|                                     | 200  | mm   |  |  |
| os per wafer                        | 358  |  |  |  |
|                                     | Photoimide   |  |  |  |
| id metal 3200nm AlSiCu              |  |  |  |  |
|                                     |  |  |  |  |
|                                     | Electrically conductive epoxy glue and soft solder |  |  |  |
|                                     | Al, ≤500µm   |  |  |  |
|                                     | Ø 0.65mm; max 1.2mm                                |  |  |  |
| for original and<br>sealed MBB bags | Ambient atmosphere air, temperature 17°C – 25°C    |  |  |  |
| for open MBB bags                   | Acc. IEC 62258-3; Section 9.4 Storage Environ      | nent.  |  |  |
|                                     | for original and<br>sealed MBB bags                | 200   as per wafer 358   Photoimide   3200nm AlSiCu   Ni Ag – system   To achieve a reliable solder connection it is stroprecommended not to consume the Ni layer complete production process   Electrically conductive epoxy glue and soft sol   Al, ≤500µm   Ø 0.65mm; max 1.2mm   for original and sealed MBB bags   Ambient atmosphere air, temperature 17°C – 2 |  |  |



#### **Maximum Ratings**

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

| Parameter                                       | Symbol             | Conditions            | Value   | Unit |
|---|--------------------|-----------------------|---------|------|
| Repetitive peak reverse voltage                 | V <sub>RRM</sub>   | T <sub>vj</sub> =25°C | 1200    | V    |
| Continuous forward current <sup>1</sup>         | I <sub>F</sub>     |                       | -       | _    |
| Maximum repetitive forward current <sup>2</sup> | I <sub>FRM</sub>   |                       | 300     | A    |
| Junction temperature                            | T <sub>vj</sub>    |                       | -40+175 | °C   |
| Operating junction temperature                  | T <sub>vj op</sub> |                       | -40+150 | °C   |

#### Static Characteristics (tested on wafer), Tvj=25°C

| Parameter                       | Symbol            | Conditions             | Value |      |      | Unit |
|---------------------------------|-------------------|------------------------|-------|------|------|------|
| Faidilletei                     | Symbol Conditions | min.                   | typ.  | max. | Unit |      |
| Reverse leakage current         | I <sub>R</sub>    | V <sub>R</sub> =1200V  | -     | -    | 26   | μA   |
| Cathode-anode breakdown voltage | V <sub>BR</sub>   | I <sub>R</sub> =0.25mA | 1200  | -    | -    | V    |
| Forward voltage drop            | $V_{F}$           | I <sub>F</sub> =45A    | 1.03  | 1.25 | 1.37 |      |

#### **Electrical Characteristics**<sup>2</sup>

| Parameter       |                               | Symbol Conditions | Conditions                  | Value |      |      | Unit |
|-----------------|-------------------------------|-------------------|-----------------------------|-------|------|------|------|
|                 |                               |                   | min.                        | typ.  | max. | Unit |      |
| Forward voltage | T <sub>vj</sub> =25°C         | V                 | 1-1504                      | 1.35  | 1.70 | 2.05 | V    |
| drop            | <i>T</i> <sub>vj</sub> =150°C | V <sub>F</sub>    | <i>I</i> <sub>F</sub> =150A | -     | 1.65 | -    | v    |

#### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

| Application example | FS150R12KT4 | Rev. 2.1 |
|---------------------|-------------|----------|
|---------------------|-------------|----------|

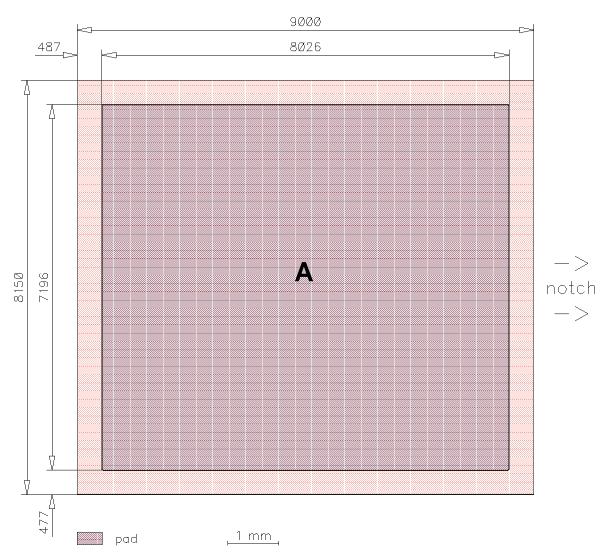
<sup>&</sup>lt;sup>1</sup> Depending on thermal properties of assembly.

<sup>&</sup>lt;sup>2</sup> Not subject to production test - verified by design/characterization.



# IDC73D120T8M

#### **Chip Drawing**



Die-Size 9000 um x 8150 um

#### A = Anode pad



#### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

#### Description

| AQL 0.65 for visual inspection according to failure catalogue     |
|---|
| Electrostatic Discharge Sensitive Device according to MIL-STD 883 |

#### **Revision History**

| Revision | Subjects (major changes since last revision) | Date       |
|----------|--|------------|
| 2.0      | Final data sheet                             | 22.08.2016 |
|          |  |            |
|          |  |            |

#### **Relevant Application Notes**





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